

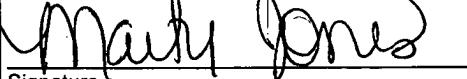


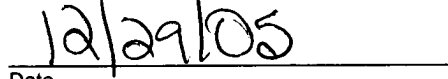
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: DALE HARRISON
Filed: SEPTEMBER 23, 2003
For: SEMICONDUCTOR PROCESSING TECHNIQUES UTILIZING
VACUUM ULTRAVIOLET REFLECTOMETER
Serial No.: 10/669,030
Group Art Unit: 2878
Examiner: HANNAHER, C.
Atty Dckt. METR:002

NUMBER: EV559591315US

I hereby certify that this paper or fee is being deposited with the United States Postal Service "EXPRESS MAIL POST OFFICE TO ADDRESSEE" service, postage prepaid, under 37 CFR 1.10 on the date indicated above and is address to: Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450.


Signature


Date

FOURTH SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97, and 1.98, it is respectfully requested that this Supplemental Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record.

In accordance with 37 C.F.R §§ 1.97(g) and (h), this Supplemental Information Disclosure Statement is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that (a) the information cited is, or is considered to be,

material to patentability as defined in 37 C.F.R. § 1.56(b); and/or (b) that the information cited is, or is considered to be prior art.

Pursuant to §1.97(c), this Supplemental Information Disclosure Statement is being submitted after the period specified in §1.97(b), but prior to the mailing of a final action under §1.113, a notice of allowance under §1.311, or an action that otherwise closes prosecution of the application, and pursuant to 37 C.F.R. § 1.97(c)(2), the fee set forth in §1.17(p) (\$180) is enclosed.

If an appropriate check has not been enclosed, or if it is insufficient, the Commissioner is hereby authorized to deduct said fee from Deposit Account No. 10-1205.

Applicant respectfully requests that the listed documents be made of record in the present case.

Respectfully submitted,



Richard D. Egan
Reg. No. 36,788
Attorney for Applicant

O'KEEFE EGAN & PETERMAN, LLP
1101 Capital of Texas Highway South
Building C, Suite 200
Austin, Texas 78746
(512) 347-1611
FAX: (512) 347-1615

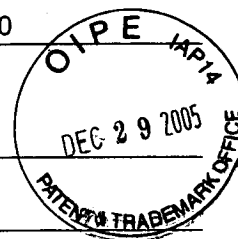
Enclosures

Form PTO-1449 (modified)

List of Patents and Publications for Applicant's

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Atty. Docket No.
METR:002Serial No.
10/669,030Applicant
Dale A. HarrisonFiling Date:
September 23, 2003Group:
2878U.S. Patent Documents
See Page 1Foreign Patent Documents
N/AOther Art
See Page 1**U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
	A31	US2002/0030826 A1	3/14/02	Chalmers et al.			7/3/01
	A32	4,368,983	1/18/83	Bennett			11/13/80

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C11	Rubloff, "Surface Reflectance Spectroscopy System", Technical Disclosure, Ip.com, www.ip.com , May 1, 1977, 5 pgs.

Examiner:**Date Considered:**

EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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Marty Jones
Signature

12/29/05
Date

THIRD SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97, and 1.98, it is respectfully requested that this Supplemental Information Disclosure Statement be entered and the document(s) listed on attached Form PTO-1449 be considered by the Examiner and made of record.

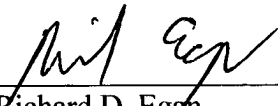
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considered to be prior art.

The references C1-C9 which we listed on the attached PTO-1449 have been previously submitted in an IDS. This Supplemental Information and Disclosure Statement provides a more full citation of each reference on the PTO-1449 form.

Applicant respectfully requests that the listed document(s) be made of record in the present case.

Respectfully submitted,

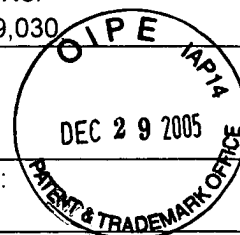


Richard D. Egan
Reg. No. 36,788
Attorney for Applicant

O'KEEFE, EGAN & PETERMAN, LLP
1101 Capital of Texas Highway South
Building C, Suite 200
Austin, Texas 78746
(512) 347-1611
FAX: (512) 347-1615

Enclosures

Form PTO-1449 (modified)		Atty. Docket No. METR:002	Serial No. 10/669,030
List of Patents and Publications for Applicant's INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		Applicant Dale A. Harrison	
		Filing Date: September 23, 2003	Group: 2878
U.S. Patent Documents See Page	Foreign Patent Documents See Page	Other Art See Pages 1-2	



U.S. Patent Documents							
Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
	A1						

Foreign Patent Documents							
Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)		
Exam. Init.	Ref. Des.	Citation
	C1	McPherson Product Brochure "Reflectometer for Sample Analysis," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-2 pps.
	C1A	McPherson Product Brochure "Spectral Reflectometer," McPherson, Inc., Massachusetts, November 12, 2001, 1 pg.
	C2	McPherson Product Brochure "VUVaS Spectrophotometers for 115 nm to >380 nm," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-4 pps.
	C3	McPherson Product Brochure "VUVaS Spectrophotometers, Made to Measure 115-380 nm," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-8 pps.
	C4	Acton Research Product Brochure "Acton Research Purged CAMS Optical Measurement System," Acton Research Corporation, Massachusetts, Published Prior to September 23, 2003, 1-2 pps.
	C5	"The Thin Film tool for next generation lithography at 157nm," Web page from http://www.sopra-sa.com , Sopra, Printed From Internet On February 19, 2002, 1pg.
	C6	"SE and GXR combined on the same instrument," Web page from http://www.sopra-sa.com , Sopra, Printed From Internet on February 19, 2002, 1pg.
	C7	"The ideal Thin Film characterization unit for Development and Pilot Line environment," Web page from http://www.sopra-sa.com , Sopra, Printed From Internet on February 19, 2002, 1 pg.

Examiner:

Date Considered:

EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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		Applicant Dale A. Harrison	
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U.S. Patent Documents <i>See Page</i>	Foreign Patent Documents <i>See Page</i>	Other Art <i>See Pages 1-2</i>	

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)		
Exam. Init.	Ref. Des.	Citation
	C8	"VUV-VASE TM , The Award Winning VUV-VASE TM is the latest addition to our line of Spectroscopic Ellipsometers," Web pages from http://www.jawoolam.com , J.A. Woollam Company, Nebraska, Printed From Internet on November 5, 2002, 1-2 pps.
	C9	"Vacuum UV Spectroscopic Ellipsometers," Web pages from http://www.sentech.de , Sentech Instruments, Printed From Internet on February 20, 2002, 1-3 pps.

Examiner:	Date Considered:
<small>EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>	